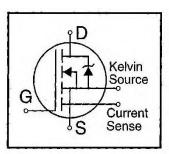
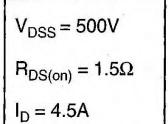
# International TOR Rectifier

# IRC830PbF

#### HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Current Sense
- Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead-Free

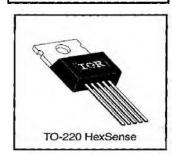




#### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The HEXSense device provides an accurate fraction of the drain current through the additional two leads to be used for control or protection of the device. These devices exhibit similar electrical and thermal characteristics as their IRF-series equivalent part numbers. The provision of a kelvin source connection effectively eliminates problems of common source inductance when the HEXSense is used as a fast, high-current switch in non current-sensing applications.



#### **Absolute Maximum Ratings**

	Parameter	Max.	Units			
ID @ Tc = 25°C	@ T <sub>C</sub> = 25°C Continuous Drain Current, V <sub>GS</sub> @ 10 V 4.5					
Ip @ Tc = 100°C	Continuous Drain Current, VGS @ 10 V 3.0		A			
Ірм	Pulsed Drain Current ①	18				
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	74	W			
	Linear Derating Factor	0.59	W/°C			
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V			
Eas	Single Pulse Avalanche Energy ②	280	mJ			
IAR	Avalanche Current ①	4.5				
EAR	Repetitive Avalanche Energy ①	7.4	mJ			
dv/dt	Peak Diode Recovery dv/dt ③	3.5	V/ns			
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C			
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)				
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)				

#### **Thermal Resistance**

	Parameter	Min.	Typ.	Max.	Units
Reuc	Junction-to-Case	_	_	1.7	
Recs	Case-to-Sink, Flat, Greased Surface		0.50	_	·°C/W
Reja	Junction-to-Ambient	_	-	62	

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	500	-	-	٧	V <sub>GS</sub> =0V, I <sub>D</sub> = 250μA	
ΔV(BR)DSS/ΔTJ	Breakdown Voltage Temp. Coefficient	-	0.61		V/°C	Reference to 25°C, ID= 1mA	
RDS(on)	Static Drain-to-Source On-Resistance	-	_	1.5	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =2.7A @	
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	-	4.0	٧	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA	
9fs	Forward Transconductance	2.7	-	-	S	V <sub>DS</sub> =50V, I <sub>D</sub> =2.7A @	
Inne	Drain-to-Source Leakage Current		-	25		V <sub>DS</sub> =500V, V <sub>GS</sub> =0V	
loss		_	-	250	μА	V <sub>DS</sub> =400V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C	
Tizzoni	Gate-to-Source Forward Leakage	_	_	100	nA	V <sub>GS</sub> =20V	
lgss	Gate-to-Source Reverse Leakage	-	-	-100	IIA	V <sub>GS</sub> =-20V	
Qg	Total Gate Charge	-	-	38		I <sub>D</sub> =3.1A	
Qgs	Gate-to-Source Charge		-	5.0	nC	V <sub>DS</sub> =400V	
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	_	-	22		V <sub>GS</sub> =10V See Fig. 6 and 13 @	
t <sub>d(on)</sub>	Turn-On Delay Time	_	8.2	-		V <sub>DD</sub> =250V	
tr	Rise Time	-	16	_	ns	I <sub>D</sub> =3.1A	
ta(off)	Turn-Off Delay Time		42	-	113	R <sub>G</sub> =12Ω	
t <sub>f</sub>	Fall Time	-	16	_		R <sub>D</sub> =79Ω See Figure 10 ®	
LD	Internal Drain Inductance	-	4.5	-	nН	Between lead, 6 mm (0.25in.) from package	
Ls	Internal Source Inductance	_	7.5	_	10.3	from package and center of die contact	
Ciss	Input Capacitance	_	610	-		V <sub>GS</sub> =0V	
Coss	Output Capacitance	i Le	91	-	pF	V <sub>DS</sub> =25V	
Crss	Reverse Transfer Capacitance	-	68	-		f=1.0MHz See Figure 5	
r	Current Sensing Ratio	1440	-	1600	-	I <sub>D</sub> =4.5A, V <sub>GS</sub> =10V	
Coss	Output Capacitance of Sensing Cells	-	9.0	_	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> = 25V, f=1.0MHz	

#### Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
Is	Continuous Source Current (Body Diode)	-	-	4.5	A	MOSFET symbol showing the	
Ism	Pulsed Source Current (Body Diode) ①	_	-	18	<b>A</b>	integral reverse G Courter p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage	_	-	1.6	٧	TJ=25°C, IS=4.5A, VGS=0V @	
trr	Reverse Recovery Time	-	320	640	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =3.1A	
Qır	Reverse Recovery Charge	/ -	1.0	2.0	μC	di/dt=100A/μs ④	
ton	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is neglegible (turn-on is dominated by Ls+Lo)				

#### Notes:

- Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ③ I<sub>SD</sub>≤4.5A, di/dt≤75A/ $\mu$ s, V<sub>DD</sub>≤V(BR)DSS, T<sub>J</sub>≤150°C
- ②  $V_{DD}$ =50V, starting  $T_J$ =25°C, L=24mH  $R_G$ =25 $\Omega$ ,  $I_{AS}$ =4.5A (See Figure 12)
- ⓐ Pulse width ≤ 300  $\mu$ s; duty cycle ≤2%.

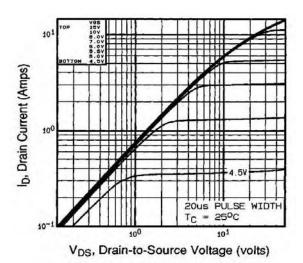
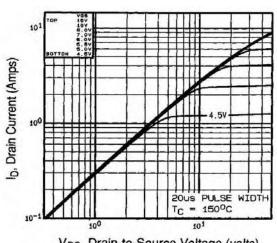


Fig 1. Typical Output Characteristics, T<sub>C</sub>=25°C



V<sub>DS</sub>, Drain-to-Source Voltage (volts)

Fig 2. Typical Output Characteristics, T<sub>C</sub>=150°C

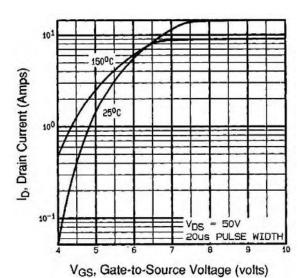


Fig 3. Typical Transfer Characteristics

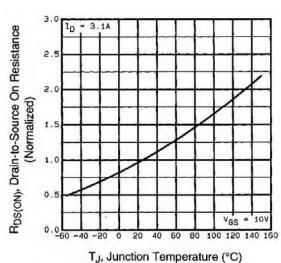


Fig 4. Normalized On-Resistance Vs. Temperature

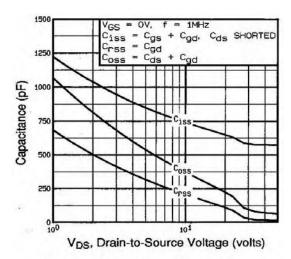


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

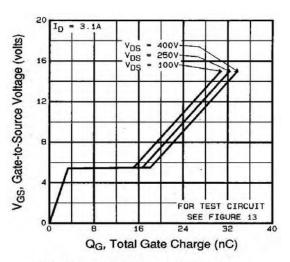


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

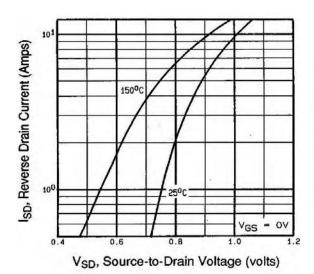


Fig 7. Typical Source-Drain Diode Forward Voltage

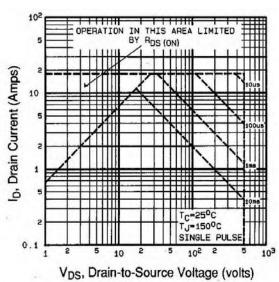


Fig 8. Maximum Safe Operating Area

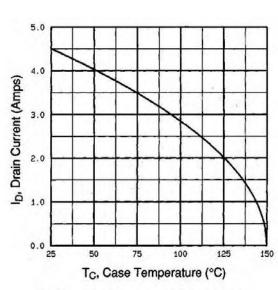


Fig 9. Maximum Drain Current Vs. Case Temperature

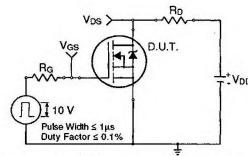


Fig 10a. Switching Time Test Circuit

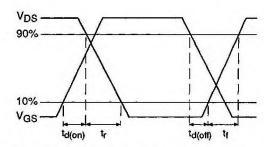


Fig 10b. Switching Time Waveforms

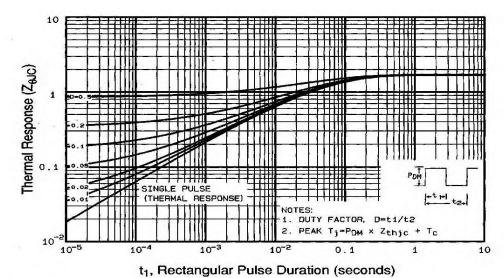


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

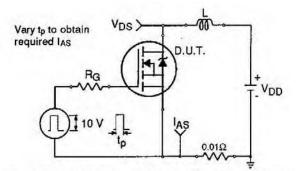


Fig 12a. Unclamped Inductive Test Circuit

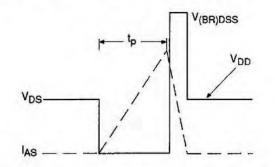


Fig 12b. Unclamped Inductive Waveforms

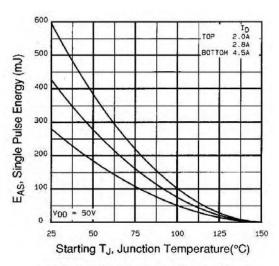


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

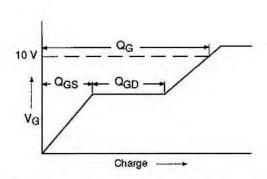


Fig 13a. Basic Gate Charge Waveform

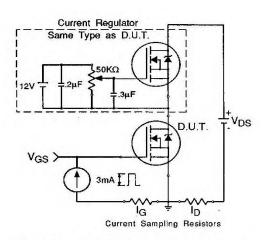


Fig 13b. Gate Charge Test Circuit

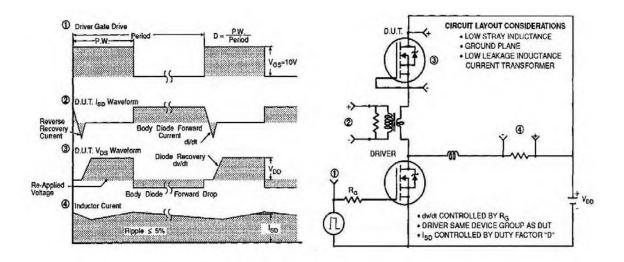


Fig 14. Peak Diode Recovery dv/dt Test Circuit

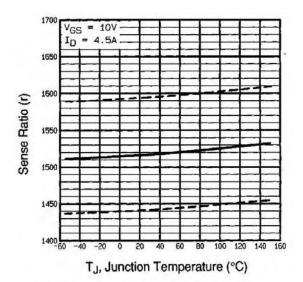


Fig 15. Typical HEXSense Ratio Vs. Junction Temperature

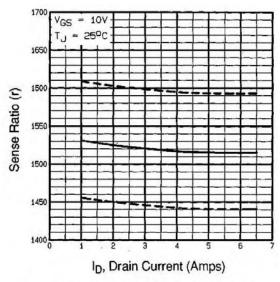


Fig 16. Typical HEXSense Ratio Vs. Drain Current

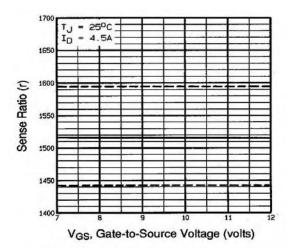


Fig 17. Typical HEXSense Ratio Vs. Gate Voltage

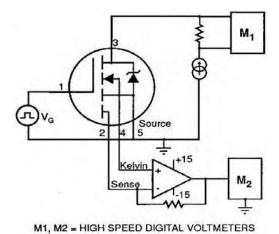


Fig 18. HEXSense Ratio Test Circuit

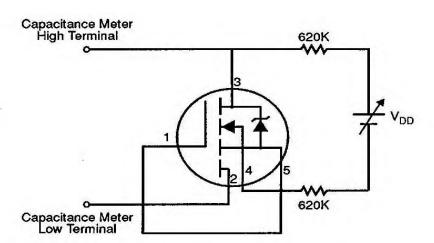
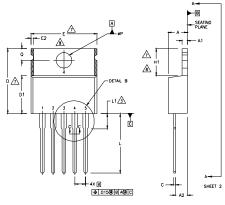


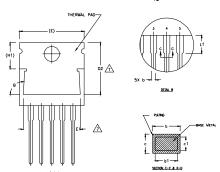
Fig 19. HEXSense Sensing Cell Output Capacitance Test Circuit

# IRC830PbF

## HexsenseTO-220 5L Package Outline

( Dimensions are shown in millimeters (inches)





- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONING AND TOLERANCING PER ASME 114.5 M— 1994.

  DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

  LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

  DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH

  SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE

  MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLY TO BASE METAL ONLY.

  CONTROLLING DIMENSION: INCHES.

  THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1

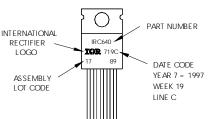
  - DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

SYMBOL	MILLIM	ETERS	INCHES		1	
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	3,56	4,82	,140	.190		
A1	0.51	1.40	.020	.055		
A2	2.04	2.92	.080	.115		
ь	0,64	0.88	.025	.035		
b1	0.64	0.84	.025	.033	5	
С	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
l <sub>D</sub> l	14,22	16.51	,560	.650	4	
D1	8.38	9.02	.330	.355		
D2	12.19	12.88	,480	.507	7	
l e l	9.66	10.66	.380	.420	4,7	
E1	8.38	8.89	.330	.350	7	
e	1,70	1,70 BSC		.067 BSC		
H1	5,85	6.55	.230	.270	7,8	
L	13.47	14,09	.530	.555		
L1	-	6.35	-	.250	3	
øΡ	3.54	4.08	.139	.161		
Q	2.54	3,42	.100	.135		
ø	90"-	-93*	90*-	-93*		

# Hexsense TO-220 5L Part Marking Information

EXAMPLE: THIS IS AN IRC640 WITH ASSEMBLY LOT CODE 1789 ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free



Data and specifications subject to change without notice.

International IOR Rectifier

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Vishay

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